Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,308	VIEIRA ET AL.	
Examiner	Art Unit	
Hanh Phan	2613	

SEARCHED					
Class	Subclass	Date	Examiner		
398	175	09/12/06	H		
	176				
	152				
	65				
	79				
359	326	09/12/06	HIP		
	332,3	30			
	344,3	31			
	333				
385	1,2	09/12/06	NP		
	4,5				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
398	175,176	09/12/06	HP		
	152,65				
359	326,332	07/12/06	пр		
	330,331 333,341				
385	1,2,4,5	09/12/06	HI		

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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